

(47911-A)



**IN THE UNITED STATES
PATENT AND TRADEMARK OFFICE**

Applicant : LONG, Yicheng et al.
Serial No. : 10/686,725
Filed : October 17, 2003
Title : NIR SPECTROSCOPY METHOD FOR ANALYZING
CHEMICAL PROCESS COMPONENTS
Art Unit : 2878

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450
United States of America

STATEMENT UNDER 37 C.F.R 1.56

Dear Sir:

This Information Disclosure Statement is submitted:

- under 37 CFR 1.97(b)

Enclosed herewith is form PTO-1449:

- copies of cited references are enclosed.

It is requested that the information disclosed herein be made of record in this application.

This statement is not intended to represent that a search has been made or that no better art exists. Further, the undersigned has no specific knowledge of the effective dates for purposes of qualification as prior art of the cited references, copies enclosed. Consequently,

.../2

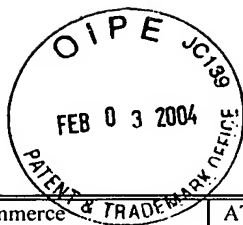
the applicant reserves the right to contest the applicability of these references as prior art against the subject application should it be determined that they are not available as prior art.

Respectfully submitted,

By 

Norris M. Eades
Registration No. 25,263

KIRBY EADES GALE BAKER
Box 3432, Stn. D
Ottawa, Ontario
Canada K1P 6N9
Tel (613) 237-6900
February 2, 2004

Sheet 1 of 1Form PTO-1449
(Rev.7-80)U.S. Department of Commerce
Patent & Trademark OfficeATTY. DOCKET NO.
47911-ASERIAL NO.
10/686,725**LIST OF REFERENCES CITED BY APPLICANT**
(Use several sheets if necessary)APPLICANT
LONG, Yicheng et al.FILING DATE:
October 17, 2003GROUP ART UNIT:
2878**U.S. PATENT DOCUMENTS**

*Examiner Initial	Kind Codes	Document Number	Date	Name	Class	Subclass	Filing Date
	B1	4,843,247	06/27/1989	Yamazoe, et al.	250	573	11/07/1986
	B1	5,672,873	09/30/1997	Yamazoe	250	339.12	07/12/1996
	B1	5,742,064	04/21/1998	Infante	250	458.1	04/24/1996
	B1	6,087,662	07/11/2000	Wilt, et al.	250	339.12	05/22/1998
	B1	6,281,489	08/28/2001	Tubel, et al.	250	227.14	05/01/1998
	B1	6,300,633	10/09/2001	Hunt, et al.	250	339.12	07/06/1998

FOREIGN PATENT DOCUMENTS

		Document number	Date	Country	Class	Subclass	Translation

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner

Date considered

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.